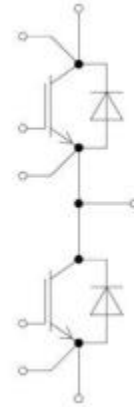


1 Features



IGBT

Half bridge IGBT modules

$V_{CES} = 1200$

**$V_{IC\ nom} =$
450 A**

Typical Applications

- Switching mode power supply
- AC and DC servo drive amplifier
- UPS Systems

Electrical Features

- Low V_{CEsat}
- Low Switching Losses
- Fast switching and short tail current

Mechanical Features

- 4kV Insulation
- High Creepage and Clearance Distances
- High Power Density

Product Name	Package	Version	Date
SPM450V120Y62HS	62mm	V1.1	2025.10.28



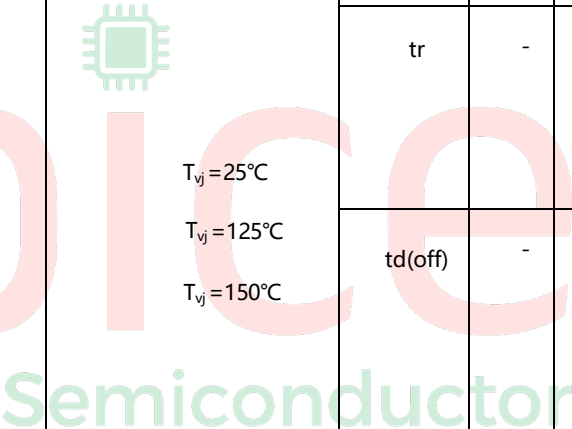
2 IGBT (Inverter)

2.1 Maximum Rated Values

Parameter	Test Conditions	Symbol	Value	Unit
Collector-emitter voltage	$T_{vj} = 25^{\circ}\text{C}$	V_{CES}	1200	V
Continuous DC collector current	$T_F = 75^{\circ}\text{C}, T_{vj} = 150^{\circ}\text{C}$	$I_{C\text{ nom}}$	450	A
Repetitive peak collector current	$t_p = 1\text{ms}, T_{vj} = 25^{\circ}\text{C}$	I_{CRM}	900	A
Gate-emitter peak voltage	$T_{vj} = 25^{\circ}\text{C}$	V_{GES}	± 20	V
Total power dissipation	$T_C = 100^{\circ}\text{C}, T_{vj} = 150^{\circ}\text{C}$	P_{tot}	595	W

2.2 Characteristic Values

Parameter	Test Conditions	Symbol	Value			Unit
			min	typ	max	
Collector-emitter saturation voltage	$I_C = 450\text{ A}, V_{GE} = 15\text{V},$	$V_{CE\text{ sat}}$	-	$T_{vj} = 25^{\circ}\text{C}$ 1.67	1.9	V
	$T_{vj} = 125^{\circ}\text{C}$ 1.93			-		
	$T_{vj} = 150^{\circ}\text{C}$ 2.01			-		
Gate threshold voltage	$I_C = 17.1\text{ mA}, V_{CE} = V_{GE}, T_{vj} = 25^{\circ}\text{C}$	V_{GEth}	5.0	6.1	6.5	V
Gate charge	$V_{GE} = -15\text{V} \dots 15\text{V}$	Q_G	-	6.08	-	μC
Internal gate resistor	$T_{vj} = 25^{\circ}\text{C}$	R_{Gint}	-	0.7	-	Ω
Input capacitance	$f = 1000\text{K Hz}, V_{CE}$	C_{ies}	-	61	-	nF

Output capacitance	$=25V,$ $V_{GE}=0V,$ $T_{vj}=25^{\circ}C$		C_{oes}	-	TB D	-	nF
Reverse transfer capacitance			C_{res}	-	1.0 4	-	nF
Collector-emitter cut-off current	$V_{CE}=1200V, V_{GE}=0V, T_{vj}=25^{\circ}C$		I_{CES}	-	-	1	mA
Gate-emitter leakage current	$V_{CE}=0V, V_{GE}=20V, T_{vj}=25^{\circ}C$		I_{GES}	-	-	30 0	nA
Turn-on delay time, inductive load	$I_C=450 A,$ $V_{CE}=600 V,$ $V_{GE}=-15 V/+15 V,$ $R_{G(on)}=2 \Omega,$ $R_{G(off)}=2 \Omega$		$td(on)$	-	21 0	-	ns
Rise time, inductive load					22 0		
					22 0		
					60 80 90		
Turn-off delay time, inductive load					$T_{vj}=25^{\circ}C$ $T_{vj}=125^{\circ}C$ $T_{vj}=150^{\circ}C$		
Fall time, inductive load	57 0						
	57 0						
Turn-on energy loss per pulse		E_{on}	-	26. 4	-	mj	
Turn-off energy loss per pulse		E_{off}	-	41.	-		

					7		
					54.7		
					60.3		
SC data	$V_{GE} \leq 15V, V_{CC} = 600V, tp \leq 8\mu s, T_{vj} = 150^\circ C$	$V_{CEmax} = V_{CES} - L_{sCE} \cdot di/dt$	I_{SC}	-	3184	-	A
Thermal resistance, junction to case	per IGBT		R_{thJC}	-	-	0.084	K/W



3 Diode (Inverter)

3.1 Maximum Rated Values

Parameter	Test Conditions	Symbol	Value	Unit
Repetitive peak reverse voltage	$T_{vj}=25^{\circ}\text{C}$	V_{RRM}	1200	V
Continuous DC forward current		I_F	450	A
Repetitive peak forward current	$t_p=1\text{ms}$, $T_{vj}=25^{\circ}\text{C}$	I_{FRM}	900	A
I^2t -Value	$t_p=10\text{ms}$, $T_{vj}=125^{\circ}\text{C}$	I^2t	TBD	A^2s

3.2 Characteristic Values

Parameter	Test Conditions		Symbol	Value			Unit
				Min	Typ	Max	
Forward voltage	$I_F=450\text{A}$, $V_{GE}=0\text{V}$,	$T_{vj}=25^{\circ}\text{C}$	V_F	1.73	2.4	V	
		$T_{vj}=125^{\circ}\text{C}$		1.69	-		
	$T_{vj}=150^{\circ}\text{C}$	1.67		-			
Peak reverse recovery current	$I_F=450\text{A}$, $V_R=600\text{V}$,	$T_{vj}=25^{\circ}\text{C}$	I_{RM}	-	318	-	A
		$T_{vj}=125^{\circ}\text{C}$		409			
		$T_{vj}=150^{\circ}\text{C}$		436			
Recovered charge	$V_{GE}=-15\text{V}$,	$T_{vj}=150^{\circ}\text{C}$	Q_r	-	9.0	-	μC
					17.		

					0		
					22.3		
Reverse recovery energy			E_{rec}	-	20.9	-	mJ
					39.6		
					47.1		
Thermal resistance, junction to case	per diode		R_{thJC}	-	-	0.14	K/W



4 Module

Parameter	Test Conditions	Symbol	Value			Unit
			min	typ	max	
Isolation test voltage	RMS, f = 50 Hz, t = 1 min	V_{ISOL}	4000			V
Material of module baseplate			Cu/Ni			
Internal isolation			Al ₂ O ₃			
Creepage distance	terminal to terminal	d_{Creep}	23			mm
	terminal to heatsink		27			
Clearance	terminal to terminal	d_{Clear}	11			mm
	terminal to heatsink		21			
Comperative tracking index		CTI	> 200			
Stray inductance module		L_{sCE}	-	20	-	nH
Temperature under switching conditions		$T_{vj,op}$	-	-	150	°C
Storage temperature		T_{stg}	-	-	125	°C
Mounting torque for modul mounting		M	3	-	6	Nm
Terminal connection torque		M	2.5	-	5	Nm
Weight		G	-	340	-	g

5 Characteristics diagrams

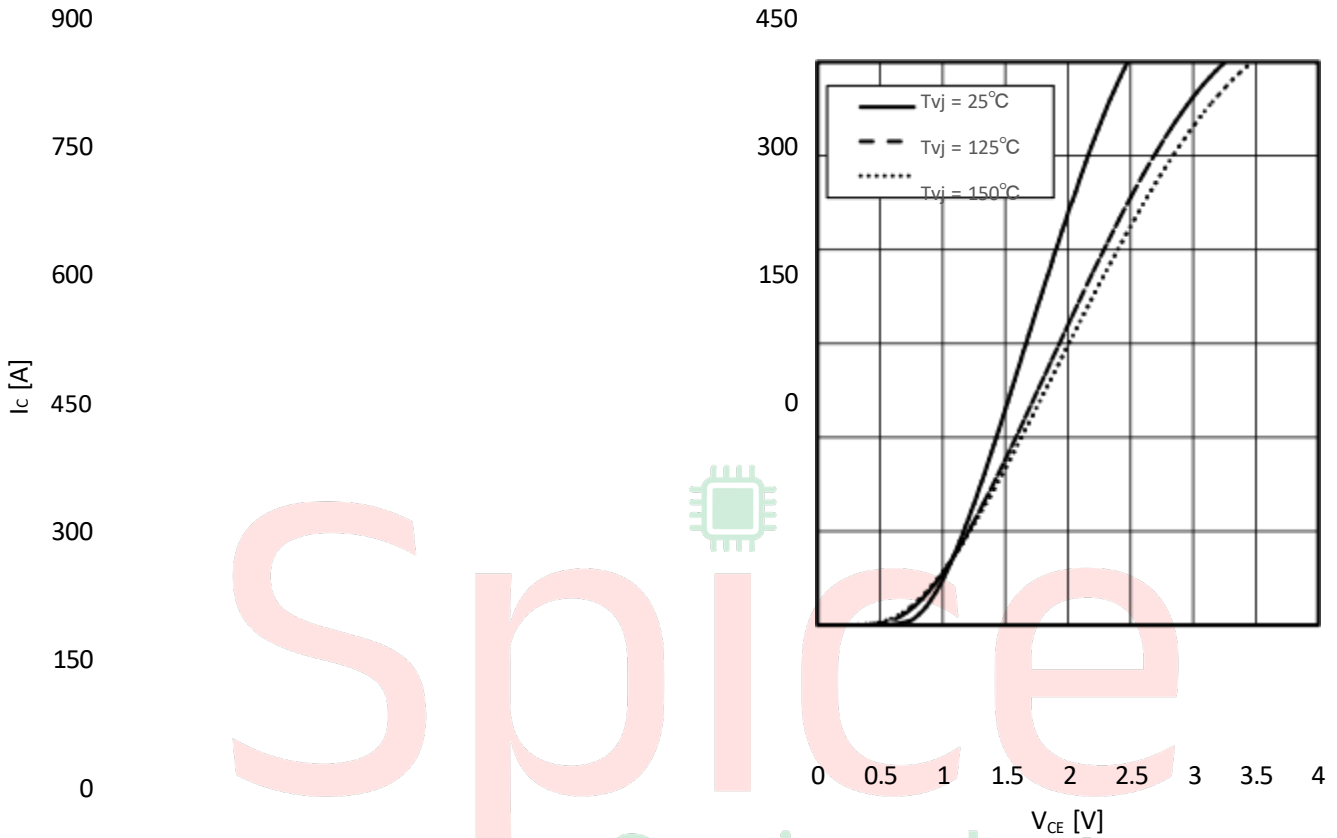
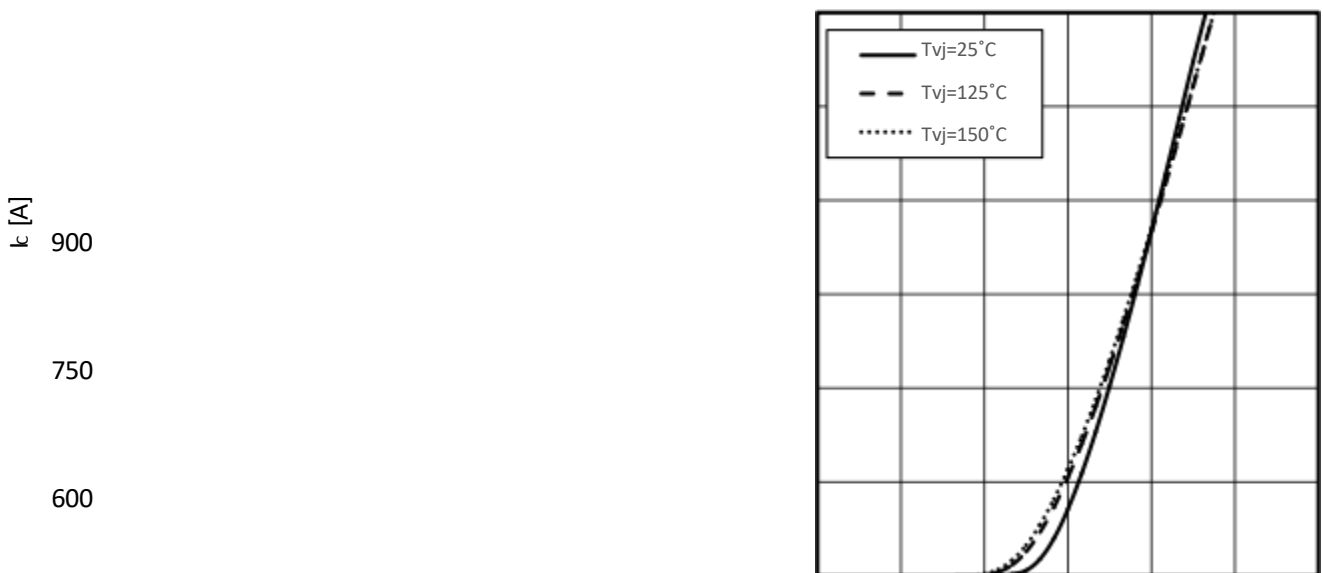


Figure 1 : Output characteristic (IGBT)

$$I_c = f(V_{CE}) , V_{GE} = 15V$$



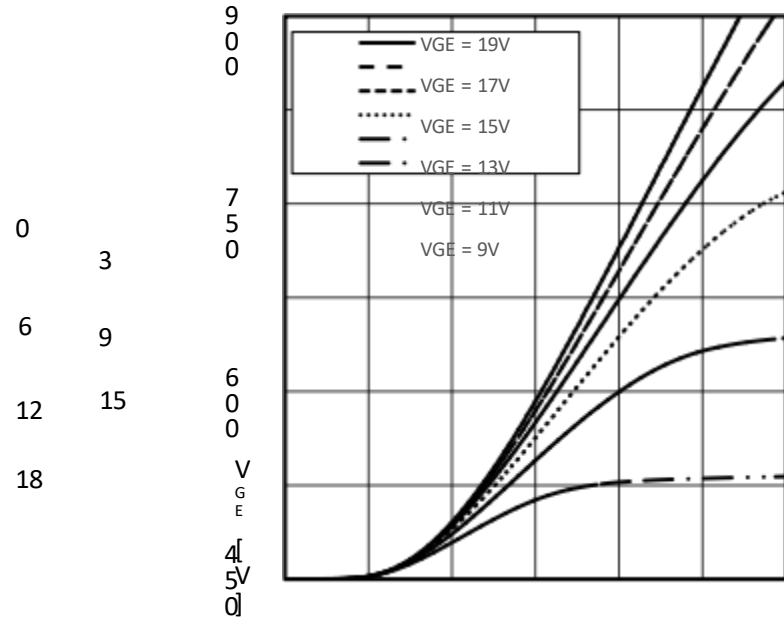


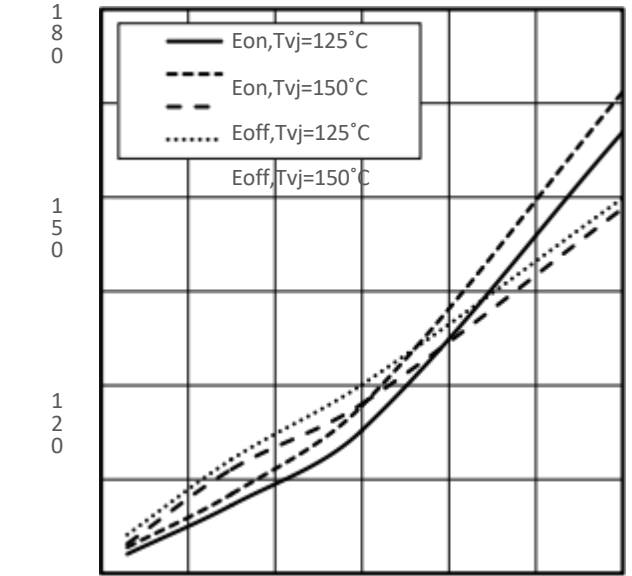
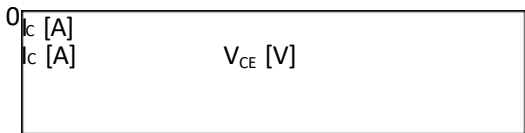
Figure 3
: Transfer characteristic

$I_c = f(V_{GE})$
, $V_{CE} = 20V$

150

0 0.5 1 1.5 2 2.5

3



90
60
30
0

E [mJ]

Figure 4: Switching losses (

IGBT) $E_{on} = f(I_c)$, $E_{off} = f(I_c)$,

$R_{Goff} = 2 \Omega$, $R_{Gon} = 2 \Omega$, $V_{CE} = 600 V$,

$V_{GE} = \pm 15 V$

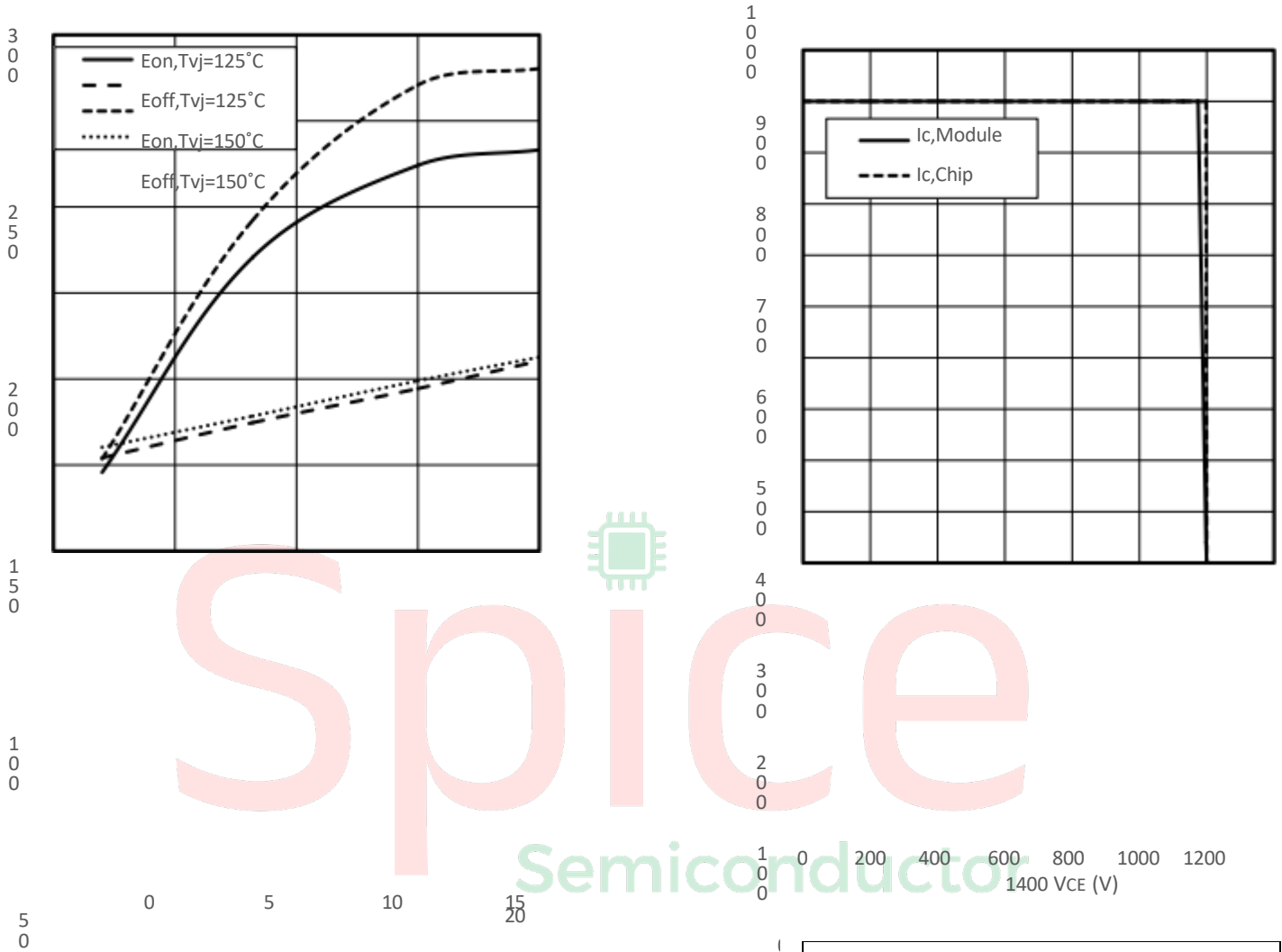
0

300

600

900

I_c [A]



Spice
Semiconductor

Figure 7 : RBSOA (IGBT) $I_c = f(V_{CE})$, $V_{GE} = \pm 15V$, $R_{Goff} = 2\Omega$, $T_{vj} =$

Figure 5 : Switching losses (IGBT)
 $E_{on} = f(R_G)$, $E_{off} = f(R_G)$
 $I_c = 450A$, $V_{CE} = 600V$, $V_{GE} = \pm 15V$

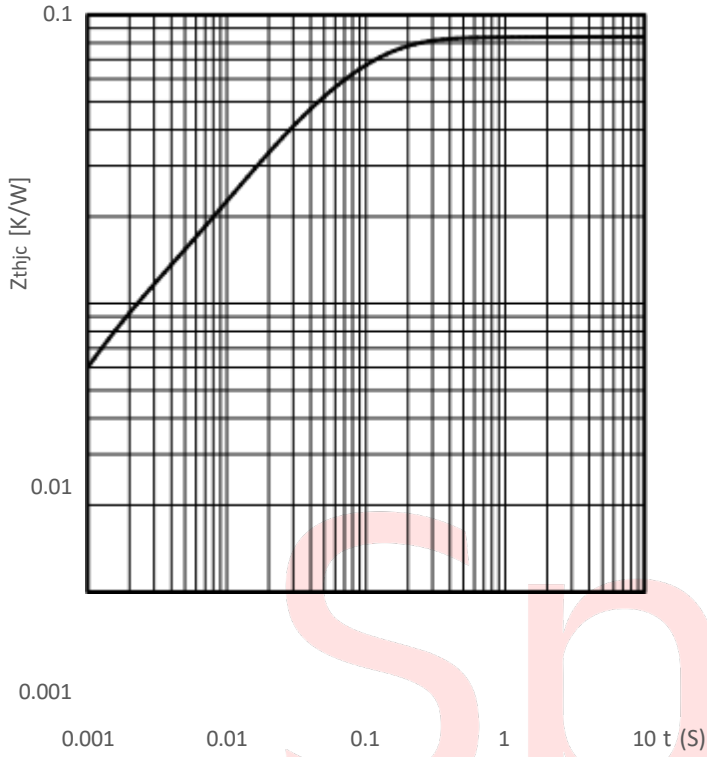


Figure 6 : Transient thermal impedance IGBT, Inverter
 $Z_{thjc} = f(t)$

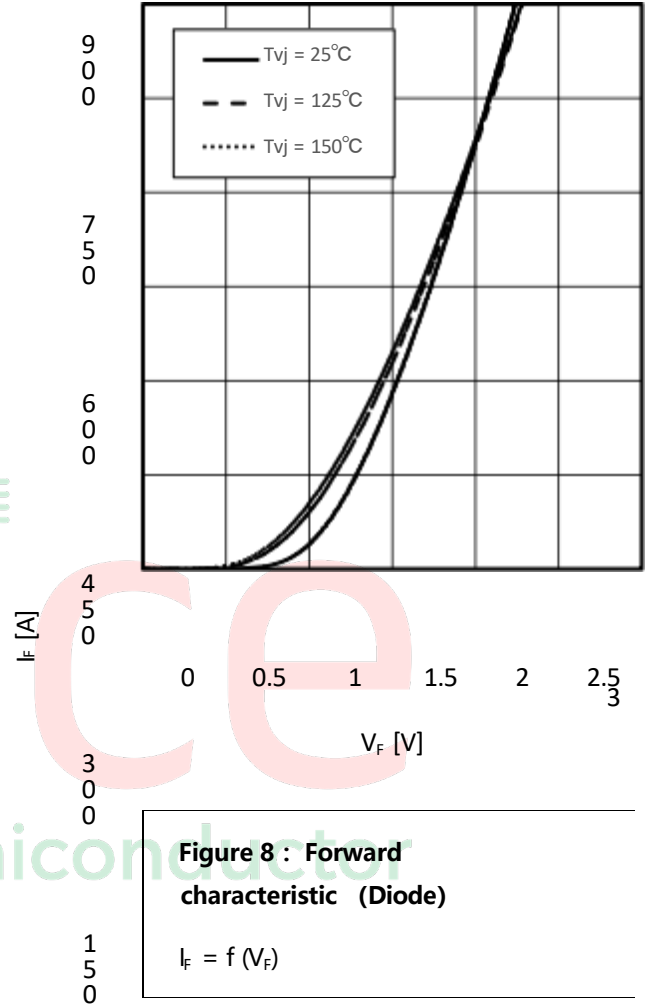


Figure 8 : Forward characteristic (Diode)
 $I_F = f(V_F)$

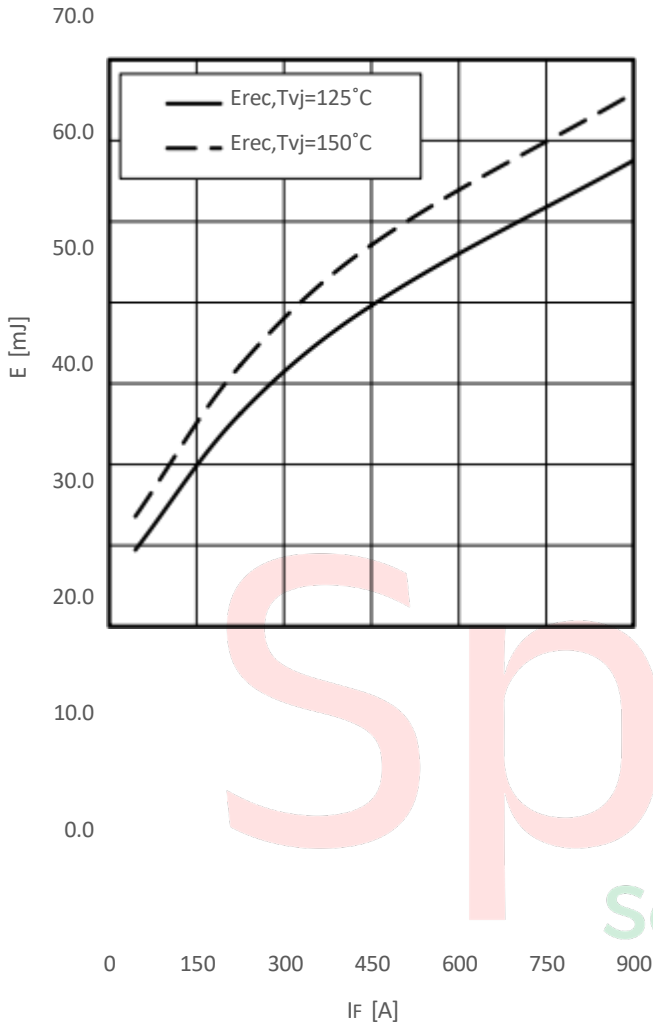


Figure 9 : Switching losses (Diode)

$E_{rec} = f(I_F), R_{Gon} = 2 \Omega, V_{CE} = 600 V$

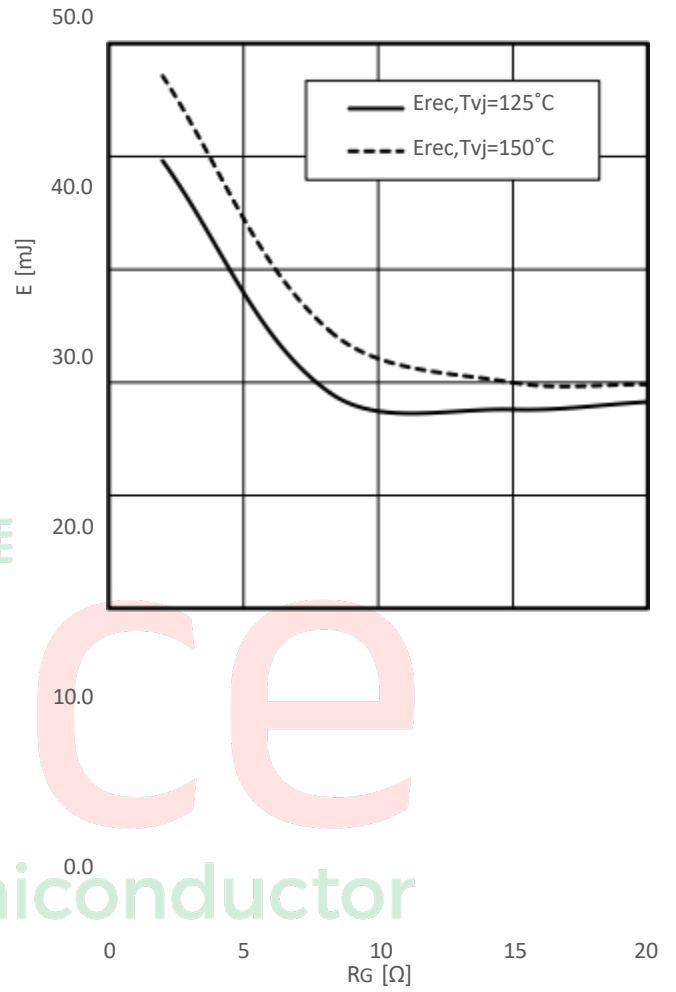


Figure 10: Switching losses (Diode)

$E_{rec} = f(R_G), I_F = 450 A, V_{CE} = 600 V$

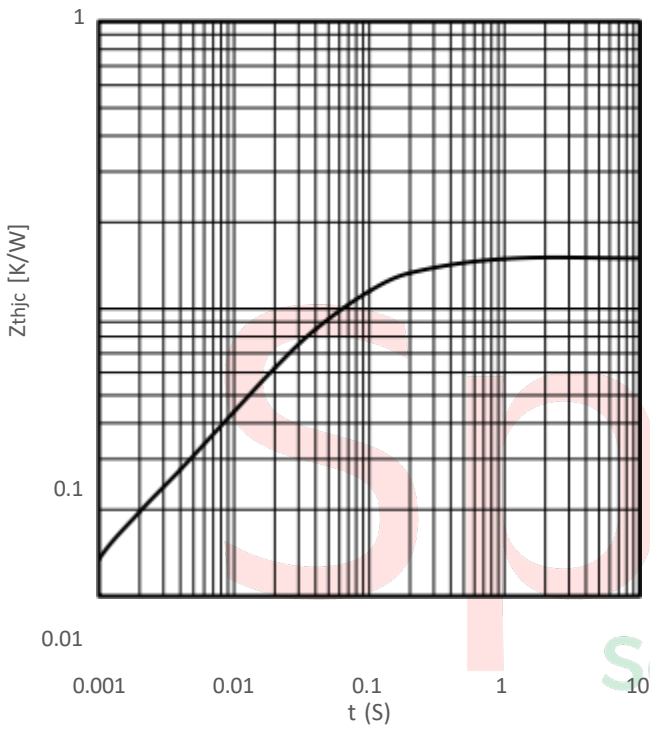
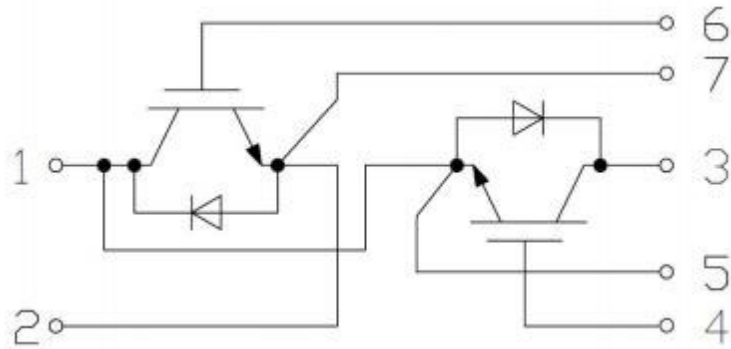


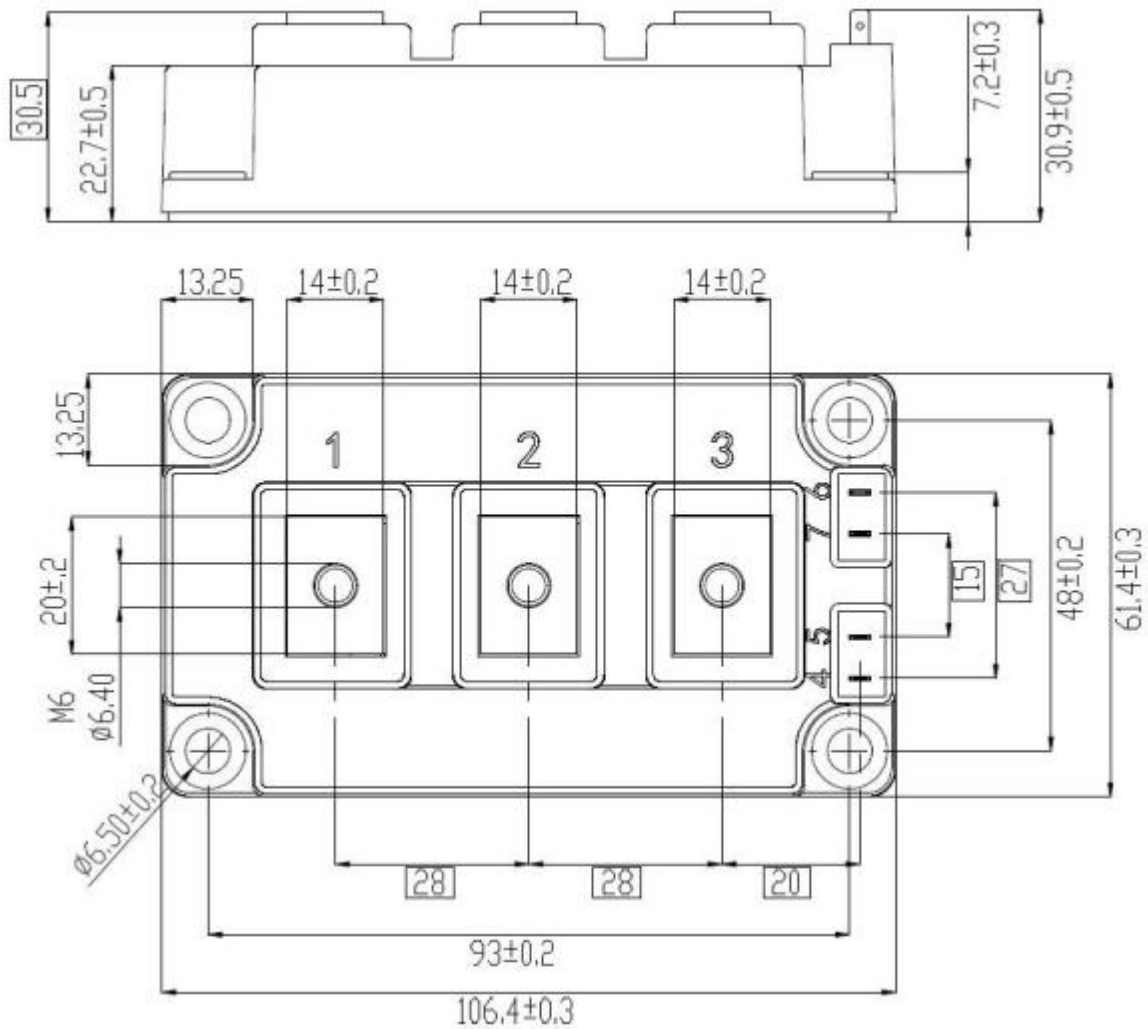
Figure 11: Transient thermal impedance Diode, Inverter

$$Z_{thjc} = f(t)$$

6 Circuit schematic



7 Package outlines: mm



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